

LC35W256EM, ET-10W

256K (32K words \times 8 bits) SRAM Control pins: $\overline{\text{OE}}$ and $\overline{\text{CE}}$

Overview

The LC35W256EM-10W and LC35W256ET-10W are asynchronous silicon-gate CMOS SRAMs with a 32768-word by 8-bit structure. These are full-CMOS devices with 6 transistors per memory cell, and feature ultralow-voltage operation, a low operating current drain, and an ultralow standby current. Control inputs include $\overline{\text{OE}}$ for fast memory access and $\overline{\text{CE}}$ for power saving and device selection. This makes these devices optimal for systems that require low power or battery backup, and makes memory expansion easy. The ultralow standby current allows these devices to be used with capacitor backup as well.

Features

Supply voltage range: 2.7 to 3.6 V
 Access time: 100 ns (maximum)
 Standby current: 0.8 μA (Ta ≤ 60°C)
 4.0 μA (Ta ≤ 70°C)

• Operating temperature: -10 to +70 °C

Data retention voltage: 2.0 to 3.6 V

- All I/O levels: CMOS compatible (0.8 V_{CC}, 0.2 V_{CC})
- Input/output shared function pins, 3-state output pins
- No clock required (fully static circuits)
- Package

28-pin SOP (450 mil) plastic package:

LC35W256EM-10W

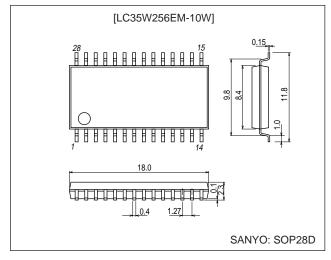
28-pin TSOP (8 × 13.4 mm) plastic package:

LC35W256ET-10W

Package Dimensions

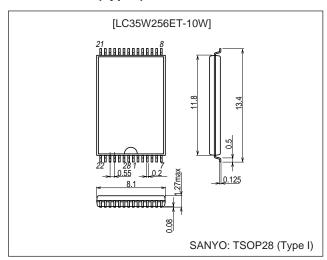
unit: mm

3187A-SOP28D



unit: mm

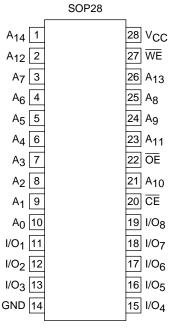
3221-TSOP28 (Type I)

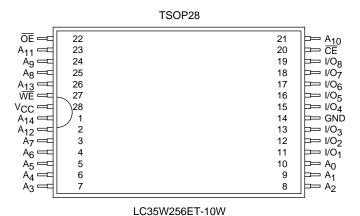


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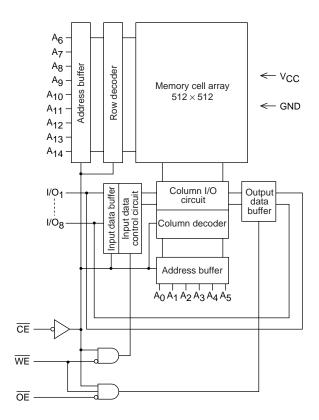
Pin Assignment (Top view)





LC35W256EM-10W

Block Diagram



Pin Functions

A0 to A14	Address input
WE	Read/write control input
ŌĒ	Output enable input
CE	Chip enable input
I/O1 to I/O8	Data I/O
V _{CC} , GND	Power supply, ground

Function Table

Mode	CE	ŌE	WE	I/O	Supply current
Read cycle	L	L	Н	Data output	I _{CCA}
Write cycle	L	X	L	Data input	I _{CCA}
Output disable	L	Н	Н	High impedance	I _{CCA}
Unselected	Н	Х	Х	High impedance	I _{ccs}

Specifications Absolute Maximum Ratings

Parameter	Symbol	Conditions Ratings		
Maximum supply voltage	V _{CC} max		4.6	V
Input pin voltage	V _{IN}		-0.3* to V _{CC} + 0.3	V
I/O pin voltage	V _{I/O}		-0.3 to V_{CC} + 0.3	V
Operating temperature	Topr		-10 to +70	°C
Storage temperature	Tstg		-55 to +125	°C

Note: * The minimum value is –2.0 V for pulse widths under 30 ns.

I/O Capacitances at $Ta = 25^{\circ}C$, f = 1 MHz

Parameter	Symbol	Conditions		Unit		
			min	typ	max	Oill
I/O pin capacitance	C _{I/O}	V _{I/O} = 0 V		6	10	pF
Input pin capacitance	Cı	V _{IN} = 0 V		6	10	pF

Note: All units are not tested; only samples are tested.

DC Allowable Operating Ranges at $Ta = -10 \ to \ +70 ^{\circ}C, \ V_{CC} = 2.7 \ to \ 3.6 \ V$

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Supply voltage	V _{CC}		2.7	3.0	3.6	V
Input voltage	V _{IH}		0.8V _{CC}		V _{CC} + 0.3	V
	V _{IL}		-0.3*		0.2V _{CC}	V

Note: * The minimum value is -2.0 V for pulse widths under 30 ns.

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DC Electrical Characteristics at $Ta = -10~to~+70^{\circ}C,\,V_{CC} = 2.7~to~3.6~V$

Parameter		Symbol	Conditions	Conditions		Ratings		
		Symbol	Conditions		min	typ	max	Unit
Input leakage current		I _{LI}	V _{IN} = 0 to V _{CC}		-1.0		+1.0	μA
Output leakage current		I _{LO}	$V_{\overline{CE}} = V_{IH} \text{ or } V_{\overline{OE}} = V_{IH} \text{ or } V_{\overline{WE}} = V_{IL}$ $V_{I/O} = 0 \text{ to } V_{CC}$		-1.0		+1.0	μΑ
Output high-level voltage		V _{OH1}	I _{OH1} = -2.0 mA		V _{CC} - 0.4			V
Output high-level voltage		V _{OH2}	I _{OH2} = -100 μA		V _{CC} - 0.1			V
Output law level veltage		V _{OL1}	I _{OL1} = 2.0 mA				0.4	V
Output low-level voltage		V _{OL2}	I _{OL2} = 100 μA				0.4	V
			$V_{\overline{CE}} = V_{IL}, I_{I/O} = 0 \text{ mA}, V_{IN} = V_{IH} \text{ or } V_{IL}$				1.2	mA
Operating current drain	CMOS inputs	1	V _{CE} = V _{IL} , V _{IN} = V _{IH} or V _{IL}	min cycle		15	18	mA
		I _{CCA3}	I _{I/O} = 0 mA, DUTY 100 %	1 µs cycle		1.5	2.5	mA
				Ta ≤ 25°C		0.01		μA
Standby mode $V_{CC} = 0.2 \text{ V}/$ 0.2 V inputs current drain	""	I _{CCS1}	$V_{\overline{CE}} \ge V_{CC} - 0.2 \text{ V},$ $V_{IN} = 0 \text{ to } V_{CC}$	Ta ≤ 60°C			0.8	μA
			Ta ≤ 70°C			4.0	μA	
	CMOS inputs	I _{CCS2}	$V_{\overline{CE}} = V_{IH}, V_{IN} = 0 \text{ to } V_{CC}$				0.4	mA

Note: * Reference values when V_{CC} = 3 V and Ta = 25°C.

AC Electrical Characteristics at $Ta=-10~to~+70^{\circ}C,\,V_{CC}=2.7~to~3.6~V$

AC test conditions

Input pulse voltage levels: 0.2 V_{CC} to 0.8 V_{CC}

Input rise and fall times: 5 ns

Input and output timing levels: $1/2\ V_{CC}$

Output load: 30 pF (including the jig capacitance)

Read Cycle

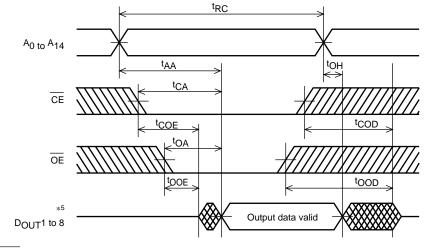
Parameter	Symbol	min	max	Unit
Read cycle time	t _{RC}	100		ns
Address access time	t _{AA}		100	ns
CE access time	t _{CA}		100	ns
OE access time	t _{OA}		50	ns
Output hold time	t _{OH}	10		ns
CE output enable time	t _{COE}	10		ns
OE output enable time	tooe	5		ns
CE output disable time	t _{COD}		35	ns
OE output disable time	t _{OOD}		30	ns

Write Cycle

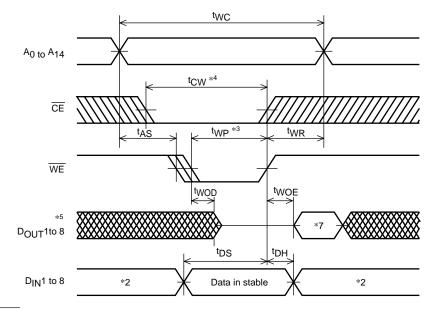
Parameter	Symbol	min	max	Unit
Write cycle time	t _{WC}	100		ns
Address setup time	t _{AS}	0		ns
Write pulse width	t _{WP}	80		ns
CE setup time	t _{CW}	90		ns
Write recovery time	t _{WR}	0		ns
CE write recovery time	t _{WR1}	0		ns
Data setup time	t _{DS}	50		ns
Data hold time	t _{DH}	0		ns
CE data hold time	t _{DH1}	0		ns
WE output enable time	t _{WOE}	5		ns
WE output disable time	t _{WOD}		35	ns

Timing Charts

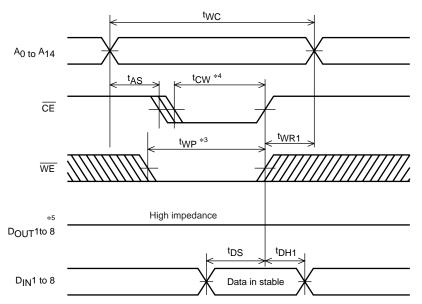
[Read cycle] *1



[Write cycle 1] ($\overline{\text{WE}}$ write) *6



[Write cycle 2] ($\overline{\text{CE}}$ write) *6



Notes:1. WE must be held at the high level during the read cycle.

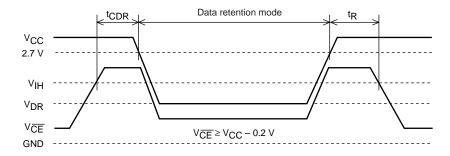
- 2. Do not apply reverse phase signals to the DOUT pins when those pins are in the output state.
- 3. The time t_{WP} is the period when both $\overline{\text{CE}}$ and $\overline{\text{WE}}$ are low. It is defined as the time from the fall of $\overline{\text{WE}}$ to the rise of $\overline{\text{CE}}$ or $\overline{\text{WE}}$, whichever occurs first
- 4. The time t_{CW} is the period when both $\overline{\text{CE}}$ and $\overline{\text{WE}}$ are low. It is defined as the time from the fall of $\overline{\text{CE}}$ to the rise of $\overline{\text{CE}}$ or $\overline{\text{WE}}$, whichever occurs first.
- 5. The D_{OUT} pins will be in the high-impedance state if any one of the following is held: OE is at the high level, CE is at the high level, or WE is at the low level.
- 6. The $\overline{\text{OE}}$ pin must be either held high or held low during the write cycle.
- 7. D_{OUT} has the same phase as the write data during this write cycle.

Data Retention Characteristics at $Ta = -10 \text{ to } +70^{\circ}\text{C}$

Parameter	Symbol	Conditions	min	max	Unit
Data retention supply voltage	V _{DR}	V _{CE} ≥ V _{CC} – 0.2 V	2.0	3.6	V
Chip enable setup time	t _{CDR}		0		ns
Chip enable hold time	t _R		t _{RC} *		ns

Note: * t_{RC}: Read cycle time

Data Retention Waveforms (CE control)



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